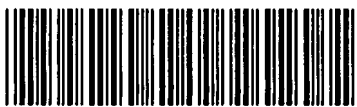


<b>Search Notes</b>  	<b>Application/Control No.</b>  10509745	<b>Applicant(s)/Patent Under Reexamination</b>  KAWAGUCHI ET AL.
	<b>Examiner</b>  Heyi, Henok G	<b>Art Unit</b>  2609

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
369	275.1 (text search only - look at search report printout)	08/16/07	Henok Heyi

<b>SEARCH NOTES</b>		
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Searched using EAST and also relied on international search report (ISR) and asked questions during QEM meeting.	08/16/07	Henok Heyi

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>